

Material Set Change:

Package Material Set		Carsem	ASE Chungli
TSSOP 16L, 20L, 24L	Die Attach	Ablestik 84-1 LMISR4	Hitachi EN4900
	Mold Compound	Sumitomo 6600H	Hitachi CEL9240HF10AK
	Wire	0.8mil, 1.0mil and 1.2/1.3 mil Gold wire	0.8mil, 1mil and 1.2/1.3mil Gold Wire

Reliability Qualification Results of TSSOP 20_24L package at ASE Chungli (AET)

QUALIFICATION RESULTS			
Test	Conditions	Sample Size	RESULT
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3 x 77	PASS
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3 x 77	PASS
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	3 x 77	PASS
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3 x 11	PASS
High Temperature Storage (HTS)	JEDEC <i>JESD22-A103</i>	1 x 77	PASS
Field Induced Charged Device Model (FICDM)	JEDEC <i>JESD22-C101</i>	3/Voltage	PASS ±1000V

*Preconditioned per JEDEC/IPC J-STD-020

Reliability Qualification Results of TSSOP 16L package at ASE Chungli (AET)

QUALIFICATION RESULTS			
Test	Conditions	Sample Size	RESULT
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3 x 77	PASS
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3 x 77	PASS
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	3 x 77	PASS
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3 x 11	PASS
High Temperature Storage (HTS)	JEDEC <i>JESD22-A103</i>	1 x 77	PASS
Field Induced Charged Device Model (FICDM)	JEDEC <i>JESD22-C101</i>	3/Voltage	PASS ±1250V

*Preconditioned per JEDEC/IPC J-STD-020